

Appl. No. 10/692,704
Amdt. sent February 23, 2004
Preliminary Amendment



PATENT

Amendments to the Specification:

Please replace paragraph 1 with the following amended paragraph:

This application claims priority to U.S. Provisional Patent Application 60/429,181, filed November 25, 2002, titled METHOD AND SYSTEM FOR MEASURING DIFFERENTIAL SCATTERING OF LIGHT OFF OF SAMPLE SURFACES, and is incorporated by reference herein for all purposes.

Respectfully submitted,

A handwritten signature in cursive script, appearing to read "Rodney C. LeRoy".

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